

| | | | | |
|-----------------------------------|---------------------------------------|--|-----------------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 09/964,985 | | Applicant(s)/Patent Under Reexamination FERTLITSCH ET AL. | |
| | Examiner BENJAMIN O. DULANEY | | Art Unit 2625 | Page 1 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|----------------------|----------------|
| * | A | US-5,128,878 A | 07-1992 | Gore et al. | 345/502 |
| * | B | US-5,287,194 A | 02-1994 | Lobiondo, Martin F. | 358/296 |
| * | C | US-5,940,186 A | 08-1999 | Barry et al. | 358/296 |
| * | D | US-5,982,996 A | 11-1999 | Snyders, Lawrence M. | 358/1.15 |
| * | E | US-6,049,394 A | 04-2000 | Fukushima, Tokutaro | 358/1.9 |
| * | F | US-2003/0011812 A1 | 01-2003 | Sesek et al. | 358/1.15 |
| * | G | US-2003/0002069 A1 | 01-2003 | Bhogal et al. | 358/1.15 |
| * | H | US-2003/0038962 A1 | 02-2003 | SHIMADA, NAOKI | 358/1.15 |
| * | I | US-2003/0048472 A1 | 03-2003 | Perdu et al. | 358/1.15 |
| * | J | US-6,609,210 B1 | 08-2003 | Onuma, Nobuo | 713/323 |
| * | K | US-6,624,909 B1 | 09-2003 | Czyszcwski et al. | 358/1.17 |
| * | L | US-6,665,082 B1 | 12-2003 | Takeoka et al. | 358/1.15 |
| * | M | US-6,863,367 B2 | 03-2005 | Hamamoto et al. | 347/23 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | | |
|---|---|-------------------------------------------------------------------------------------------|--|--|--|--|
| | U | | | | | |
| | V | | | | | |
| | W | | | | | |
| | X | | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

09/964,985

Applicant(s)/Patent Under
Reexamination
FERTLITSCH ET AL.

Examiner

BENJAMIN O. DULANEY

Art Unit

2625

Page 2 of 2

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------------------|----------------|
| * | A | US-6,891,632 B2 | 05-2005 | Schwartz, Stephen | 358/1.15 |
| * | B | US-6,985,245 B1 | 01-2006 | Takahashi, Hiroyuki | 358/1.15 |
| * | C | US-7,072,057 B1 | 07-2006 | Hansen, David R. | 358/1.15 |
| * | D | US-7,081,969 B1 | 07-2006 | Motamed et al. | 358/1.16 |
| * | E | US-7,139,085 B1 | 11-2006 | Sakaguchi, Eiji | 358/1.15 |
| * | F | US-7,148,980 B2 | 12-2006 | Tominaga, Masahiko | 358/1.15 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|-------------------------------------------------------------------------------------------|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.